Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,856	ACHARYA ET AL.
Examiner	Art Unit

2614

BINH K. TIEU

SEARCHED					
Class	Subclass	Date	Examiner		
370	351-357	6-23-07	BICT		
	260-261		7		
	264-265				
	270				
	262-263				
	399, 432				
	458, 460				
	468				
379	202.01				
	204.01				
	205.01				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
WEST DATABASES SEARCHES	6/23/2007	ВКТ
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